

ABSTRACT

A fuse for an integrated circuit is constituted by a shallow NP junction, covered with a metal contact, the semiconductor region being not excessively doped. For the blowing of the fuse, the junction is forward biased with a current sufficient to enable a diffusion of metal up to the junction. This short-circuits the junction. The detection is done also by the forward biasing of the junction, but with a low current or a low voltage. The detection can also be done with reverse biasing.